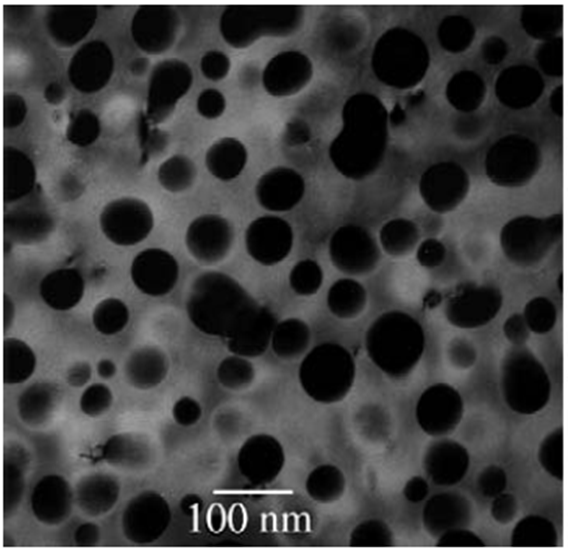
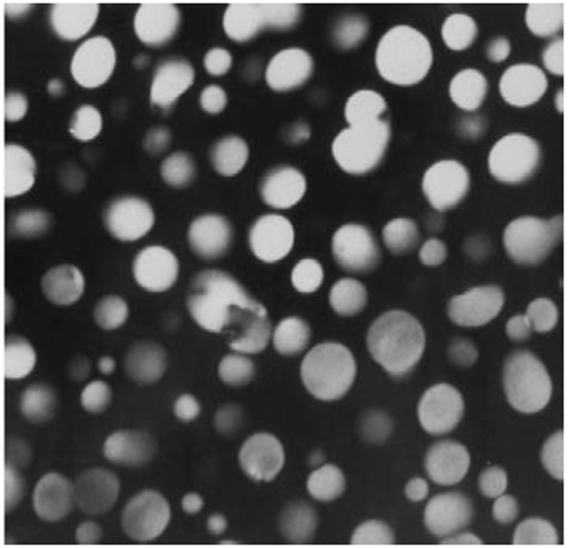


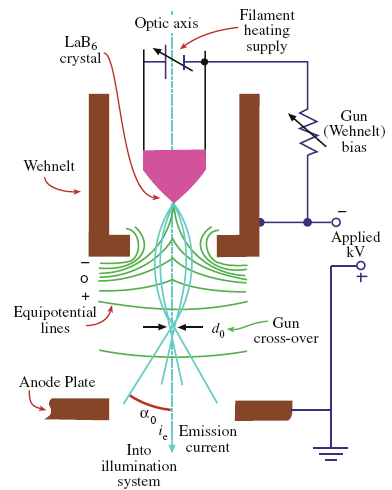
Bright Field Image



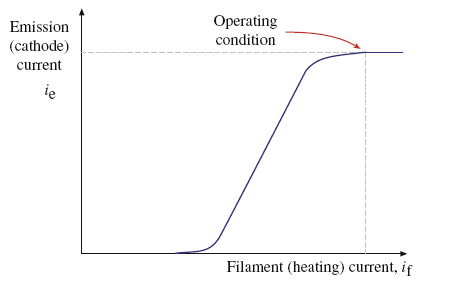
Dark Field Image



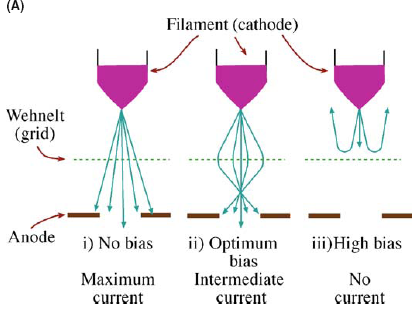
Thermionic Gun



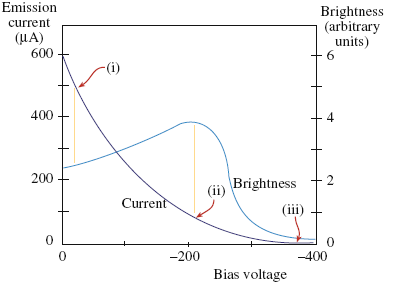
Relation between emission current and filament current



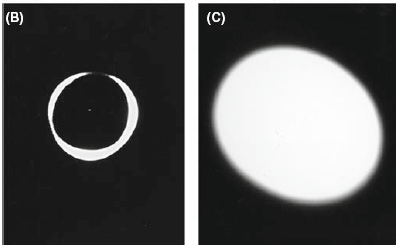
Effect of increasing Whenelt bias on the distribution of electrons coming through the anode



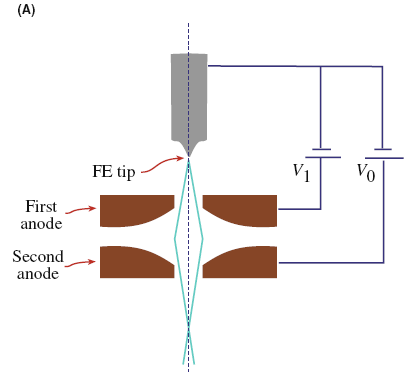
Relationship between the bias and the emission current / per gun brightness



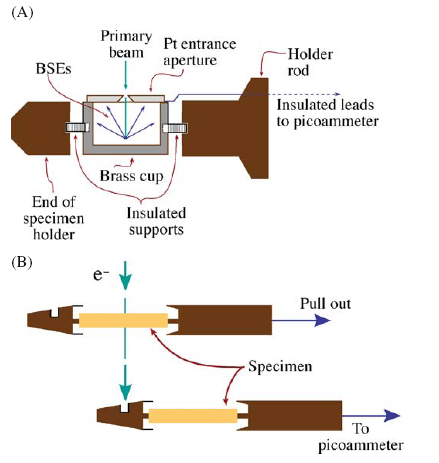
Electron Distribution when the source is at undersaturated and saturated stage

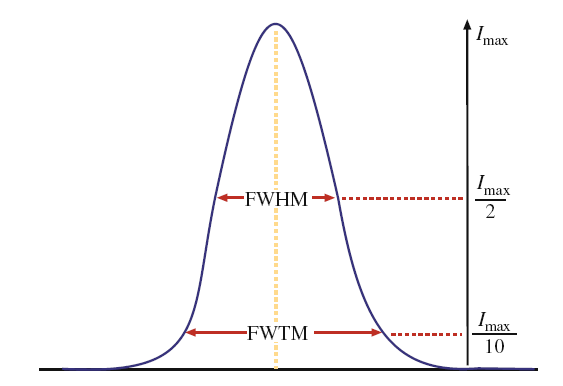


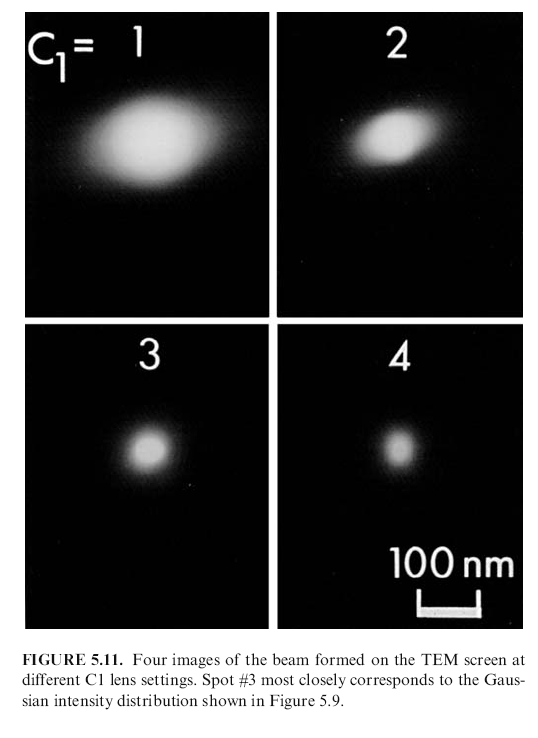
Electron paths from a FES showing how fine crossover is formed by two anodes acting as electrostatic lens



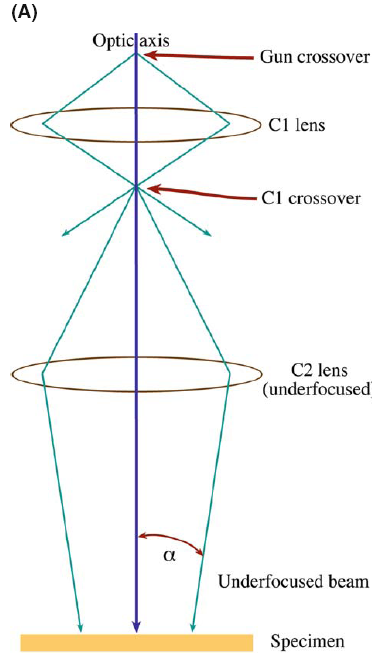
Faraday cup with side loading holder



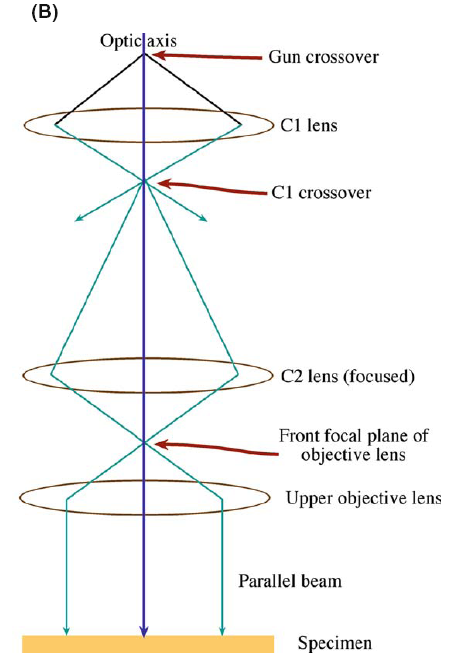


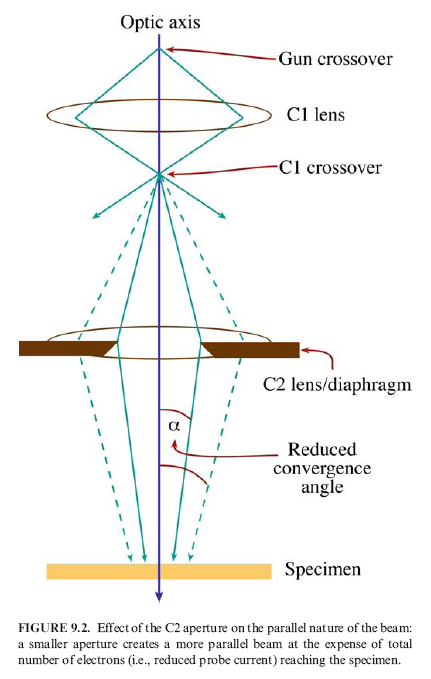


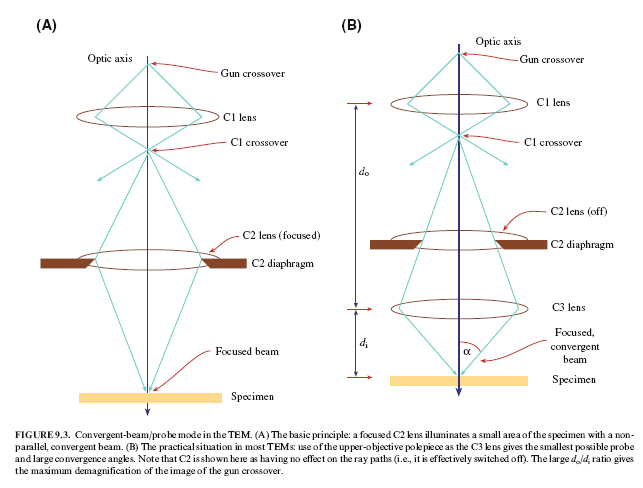
Imaging System C2 lens underfocused Parallel Beam imaging



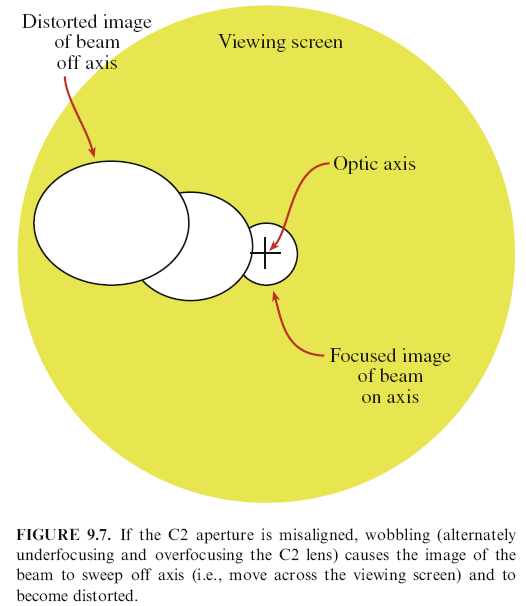
C2 lens overfocused Parallel beam imaging



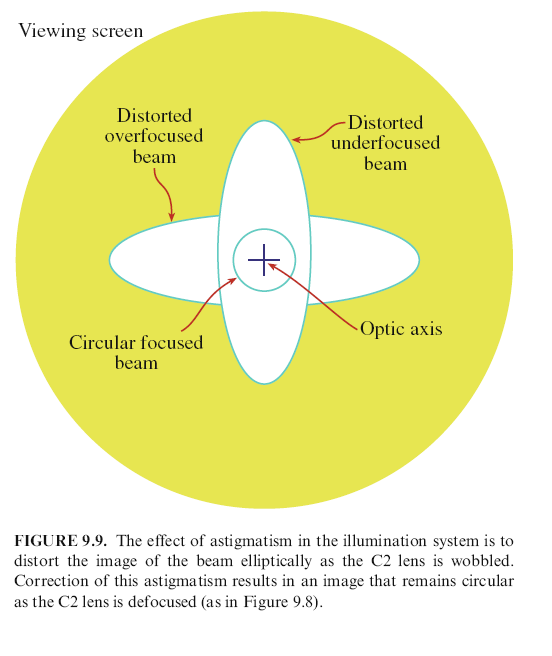




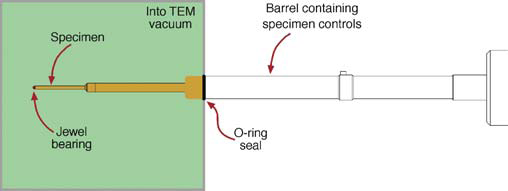


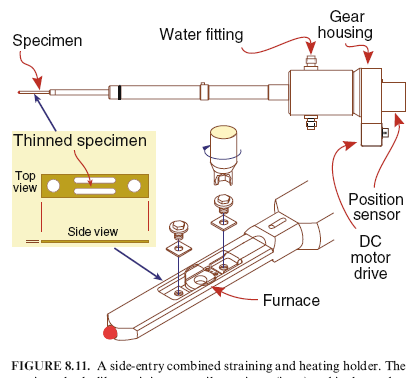


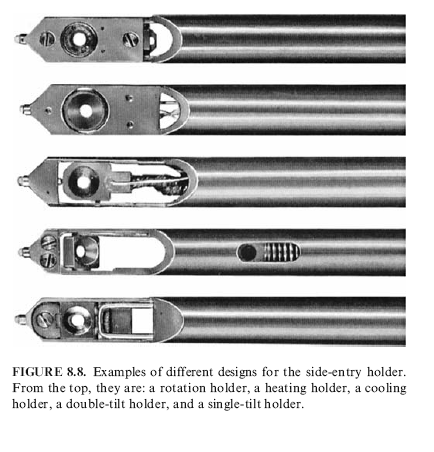


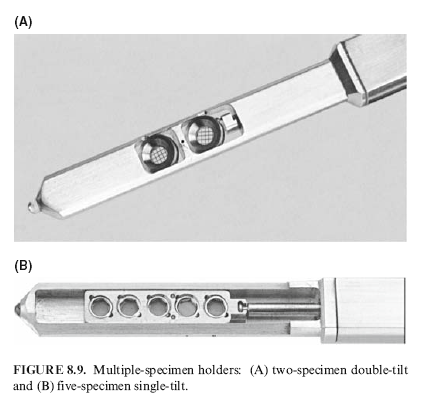


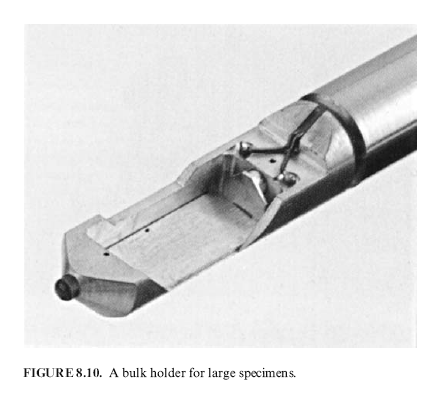
Side Entry Holder



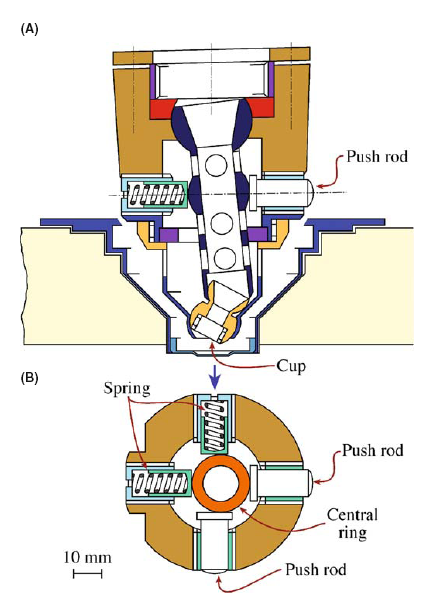


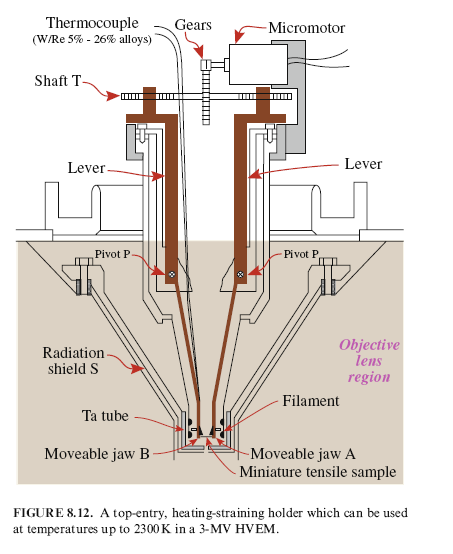






Top Entry holder, A-Cross section,B – Top view





Schematic of Plasma Cleaner

